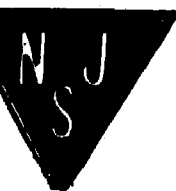
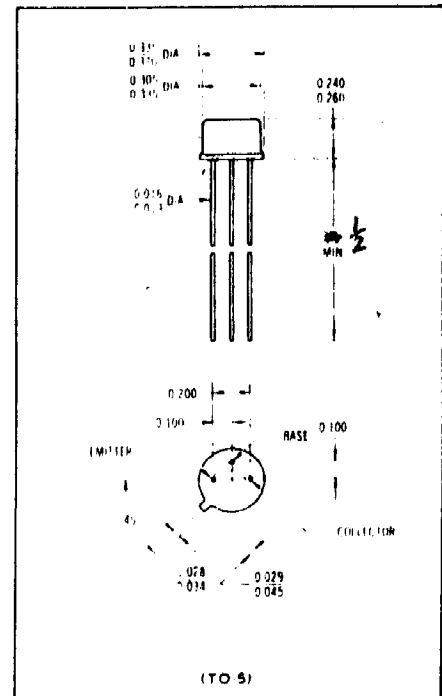


2N3762 (SILICON)

Medium-current PNP silicon annular transistor, designed for high-speed switching and driver applications.

MAXIMUM RATINGS ($T_A = 25^\circ\text{C}$ unless otherwise noted)

Rating	Symbol		Unit
Collector-Base Voltage	V_{CB}	40	Vdc
Collector-Emitter Voltage	V_{CEO}	40	Vdc
Emitter-Base Voltage	V_{EB}	5.0	Vdc
Collector Current	I_C	1.5	Adc
Total Device Dissipation @ $T_A = 25^\circ\text{C}$ Derating Factor Above 25°C	P_D	1.0 5.71	Watt mW/ $^\circ\text{C}$
Total Device Dissipation @ $T_C = 25^\circ\text{C}$ Derating Factor Above 25°C	P_D	4.0 22.8	Watts mW/ $^\circ\text{C}$
Thermal Resistance Junction to Ambient Junction to Case	θ_{JA} θ_{JC}	0.175 0.044	$^\circ\text{C}/\text{mW}$
Junction Temperature, Operating	T_J	+200	$^\circ\text{C}$
Storage Temperature Range	T_{stg}	-65 to +200	$^\circ\text{C}$



ELECTRICAL CHARACTERISTICS (T_A = 25°C unless otherwise noted)

Characteristic	Symbol	Min	Max	Unit
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OFF CHARACTERISTICS

Collector-Base Breakdown Voltage (I _C = 10 μAdc, I _E = 0)	BV _{CB0}	40	—	Vdc
Collector-Emitter Breakdown Voltage ⁽¹⁾ (I _C = 10 mAdc, I _B = 0)	BV _{CEO}	40	—	Vdc
Emitter-Base Breakdown Voltage (I _E = 10 μAdc, I _C = 0)	BV _{EBO}	6.0	—	Vdc
Collector Cutoff Current (V _{CE} = 20 Vdc, V _{EB} = 2 Vdc) (V _{CE} = 20 Vdc, V _{EB} = 2 Vdc, T _A = 100°C)	I _{CEX}	—	0.10 10	μAdc
Base Cutoff Current (V _{CE} = 20 Vdc, V _{EB} = 2 Vdc)	I _{BL}	—	0.2	μAdc

ON CHARACTERISTICS

DC Current Gain ⁽¹⁾ (I _C = 10 mAdc, V _{CE} = 1 Vdc) (I _C = 150 mAdc, V _{CE} = 1 Vdc) (I _C = 500 mAdc, V _{CE} = 1 Vdc) (I _C = 1 Adc, V _{CE} = 1.5 Vdc) (I _C = 1.5 Adc, V _{CE} = 5 Vdc)	h _{FE}	35 40 35 30 30	— — — 120 —	—
Collector Saturation Voltage ⁽¹⁾ (I _C = 10 mAdc, I _B = 1 mAdc) (I _C = 150 mAdc, I _B = 15 mAdc) (I _C = 500 mAdc, I _B = 50 mAdc) (I _C = 1 Adc, I _B = 100 mAdc)	V _{CE(sat)}	— — — —	0.1 0.22 0.5 0.9	Vdc
Base-Emitter Saturation Voltage ⁽¹⁾ (I _C = 10 mAdc, I _B = 1 mAdc) (I _C = 150 mAdc, I _B = 15 mAdc) (I _C = 500 mAdc, I _B = 50 mAdc) (I _C = 1 Adc, I _B = 100 mAdc)	V _{BE(sat)}	— — — 0.9	0.8 1.0 1.2 1.4	Vdc

TRANSIENT CHARACTERISTICS

Output Capacitance (V _{CB} = 10 Vdc, I _E = 0, f = 100 kHz)	C _{ob}	—	15	pF
Input Capacitance (V _{BE} = 0.5 Vdc, I _C = 0, f = 100 kHz)	C _{ib}	—	80	pF
High Frequency Current Gain (I _C = 50 mAdc, V _{CE} = 10 Vdc, f = 100 MHz)	h _{fe}	1.8	—	—
Delay Time	(V _{CC} = 30 V, V _{BE(off)} = 2 V, I _C = 1 Amp, I _{B1} = 100 mA)	t _d	—	8.0 ns
Rise Time		t _r	—	35 ns
Storage Time		t _s	—	80 ns
Fall Time		t _f	—	35 ns
Total Control Charge (I _C = 1 Amp, I _B = 100 mA, V _{CC} = 30 V)	Q _T	—	30	nC

⁽¹⁾ Pulse Test: PW ≤ 300 μs, Duty Cycle ≤ 2%